

FRFS-FHC40LG-001

Test fixture for testing a low noise transistor

REV 1.00



The FRFS-FHC40LG-001 is a high performance custom designed RF/Microwave production type fixture for testing Sumitomo FHC40LG or Transcom TC2384 low noise transistors. This fixture is constructed to provide repeatable measurements in a production environment. The FRFS-FHC40LG-001 test fixture feature fast load/unload clamshell type cover.

ELECTRICAL/ MECHANICAL SPECIFICATIONS

PARAMETER	SPECIFICATION*
FREQUENCY RANGE	DC – 12 GHz
RF PORTS	2
RETURN LOSS	20 dB min
INSERTION LOSS	0.3dB (per transition)
DC PINS	
MATING INTERFACE	SMA JACK (FEMALE)

Electro-Photonics LLC reserves the right to modify drawings, configurations, specifications, and design at any time without prior notification.

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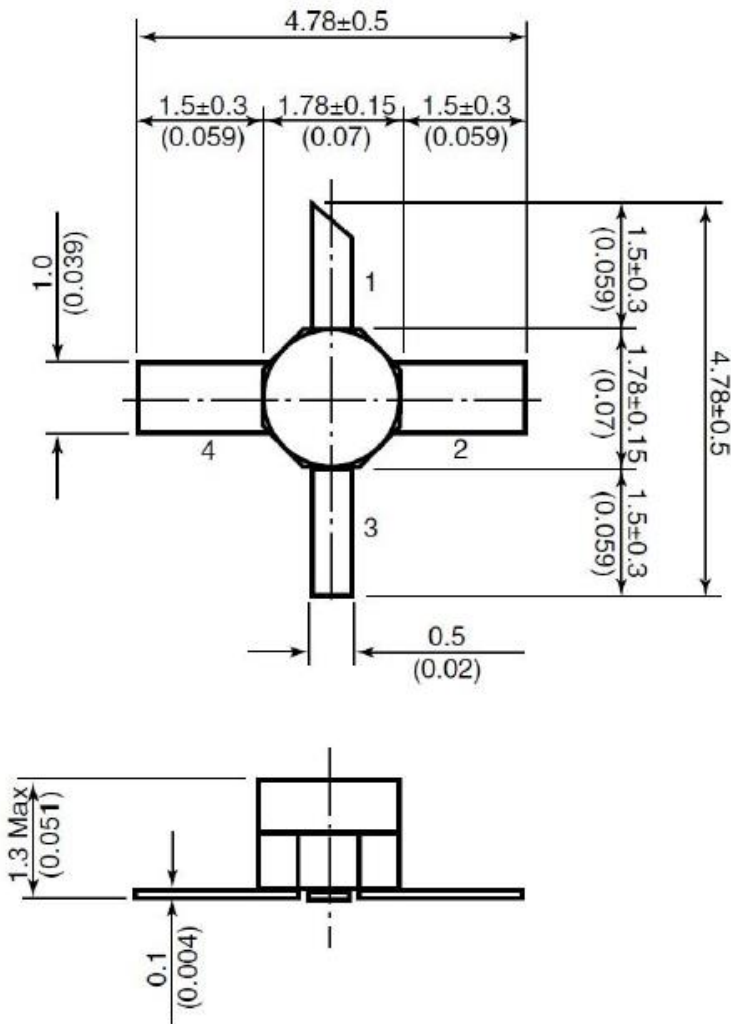
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PACKAGE FOOTPRINT

Case Style : LG

Metal-Ceramic Hermetic Package



Pin Assignment

- 1 : Gate
- 2 : Source
- 3 : Drain
- 4 : Source

Unit : mm (inches)

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CUSTOMIZATION

The FRFS-FHC40LG-001 can be customized for number of similar DUT's in this or similar footprint. In addition, Electro-Photonics can design a custom solution per your requirements.

Please consult sales sales@electro-photonics.com to discuss customization options.

ORDERING INFO

FRFS - FHC40LG-001

PRODUCT CODE

FIXTURE CODE